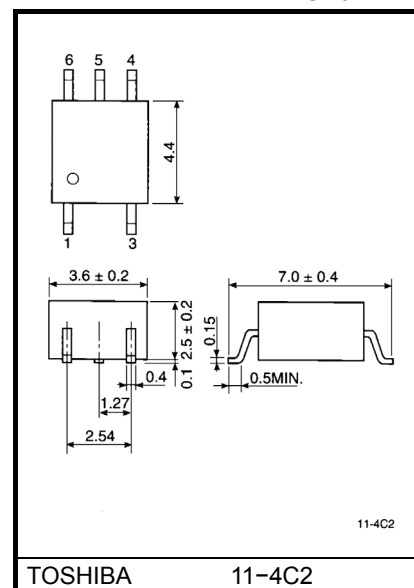


TLP114A

Transistor Inverter.

TLP114A consists of a high output power GaAlAs light emitting diode, optically coupled to a high speed detector of one chip photodiode-transistor.

- Isolation voltage: 3750 Vrms (min.)
- Switching speed: $t_{pHL} = 0.8\mu s$, $t_{pLH} = 0.8\mu s$ (max.)
($R_L = 1.9\text{ k}\Omega$)
- TTL compatible
- UL recognized: UL1577, file no. E67349



Weight: 0.09g

1 : ANODE
3 : CATHODE
4 : EMITTER (GND)
5 : COLLECTOR (OUTPUT).
6 : VCC

The circuit diagram illustrates the internal architecture of the SHIELD module. It features a voltage divider network connected to pins 1, 2, and 3. Pin 1 is labeled V_F and has an input current I_F . Pin 2 is labeled V_{CC} and has an output current I_{CC} . Pin 3 is labeled GND and has an output current I_O . The module contains two diodes and a transistor. A dashed vertical line separates the input stage from the output stage. Arrows indicate the direction of current flow through the components.

Absolute Maximum Ratings (Ta = 25°C)

Characteristic		Symbol	Rating	Unit
LDE	Forward current (Note 1)	I _F	20	mA
	Pulse forward current (Note 2)	I _{FP}	40	mA
	Peak transient forward current (Note 3)	I _{FPT}	1	A
	Reverse voltage	V _R	5	V
Detector	Output current	I _O	8	mA
	Peak output current	I _{OP}	16	mA
	Supply voltage	V _{CC}	–0.5~30	V
	Output voltage	V _O	–0.5~20	V
	Output power dissipation (Note 4)	P _O	100	mW
Operating temperature range		T _{opr}	–55~100	°C
Storage temperature range		T _{stg}	–55~125	°C
Lead solder temperature(10 sec.)		T _{sol}	260	°C
Isolation Voltage (AC, 1 min., R.H. ≤ 60%) (Note 5)		BV _S	3750	V _{rms}

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(Note 1) Derate 0.36mA / °C above 70°C.

(Note 2) 50% duty cycle, 1ms pulse width.

Derate 0.72mA / °C above 70°C.

(Note 3) Pulse width ≤ 1μs, 300pps.

(Note 4) Derate 1.8mW / °C above 70°C.

Electrical Characteristics (Ta = 25°C)

Characteristic		Symbol	Test Condition	Min.	Typ.	Max.	Unit
LDE	Forward voltage	V_F	$I_F = 16\text{mA}$	1.22	1.42	1.72	V
	Forward voltage temperature coefficient	$\Delta V_F / \Delta T_a$	$I_F = 16\text{mA}$	—	-2	—	mV / °C
	Reverse current	I_R	$V_R = 3\text{V}$	—	—	10	μA
	Capacitance between terminals	C_T	$V_F = 0, f = 1\text{MHz}$	—	30	—	pF
Detector	High level output current	$I_{OH(1)}$	$I_F = 0\text{mA}, V_{CC} = V_O = 5.5\text{V}$	—	3	500	nA
		$I_{OH(2)}$	$I_F = 0\text{mA}, V_{CC} = 30\text{V}$ $V_O = 20\text{V}$	—	—	5	μA
		I_{OH}	$I_F = 0\text{mA}, V_{CC} = 30\text{V}$ $V_O = 20\text{V}, T_a = 70^\circ\text{C}$	—	—	50	
	High level supply current	I_{CCH}	$I_F = 0\text{mA}, V_{CC} = 30\text{V}$	—	0.01	1	μA
Coupled	Current transfer ratio	I_O / I_F	$I_F = 16\text{mA}, V_{CC} = 4.5\text{V}$ $V_O = 0.4\text{V}$	20	—	—	%
	Low level output voltage	V_{OL}	$I_F = 16\text{mA}, V_{CC} = 4.5\text{V}$ $I_O = 2.4\text{mA}$	—	—	0.4	V
	Isolation resistance	R_S	R.H. $\leq 60\%$, $V_S = 500\text{V}$ (Note 5)	5×10^{10}	10^{14}	—	Ω
	Stray capacitance between input to output	C_S	$V_S = 0, f = 1\text{MHz}$ (Note 5)	—	0.8	—	pF

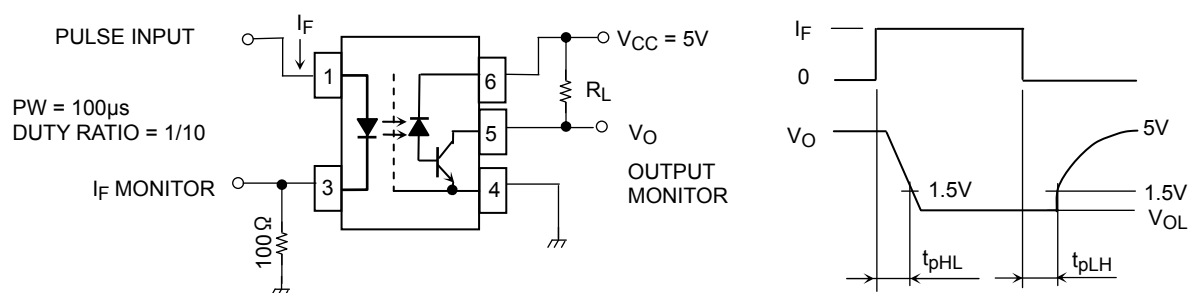
Switching Characteristics (Ta = 25°C, VCC = 5V)

Characteristic	Symbol	Test Circuit	Test Condition	Min.	Typ.	Max.	Unit
Propagation delay time (H → L)	t_{pHL}	1	$I_F = 0 \rightarrow 16\text{mA}$ $V_{CC} = 5\text{V}, R_L = 1.9\text{k}\Omega$	—	—	0.8	μs
Propagation delay time (L → H)	t_{pLH}	1	$I_F = 16 \rightarrow 0\text{mA}$ $V_{CC} = 5\text{V}, R_L = 1.9\text{k}\Omega$	—	—	0.8	μs
Common mode transient immunity at high output level	C_{MH}	2	$I_F = 0\text{mA}$, $V_{CM} = 400\text{V}_{p-p}$ $R_L = 4.1\text{k}\Omega$	5000	10000	—	V / μs
Common mode transient immunity at low output level	C_{ML}	2	$I_F = 16\text{mA}$, $V_{CM} = 400\text{V}_{p-p}$ $R_L = 4.1\text{k}\Omega$	-5000	-10000	—	V / μs

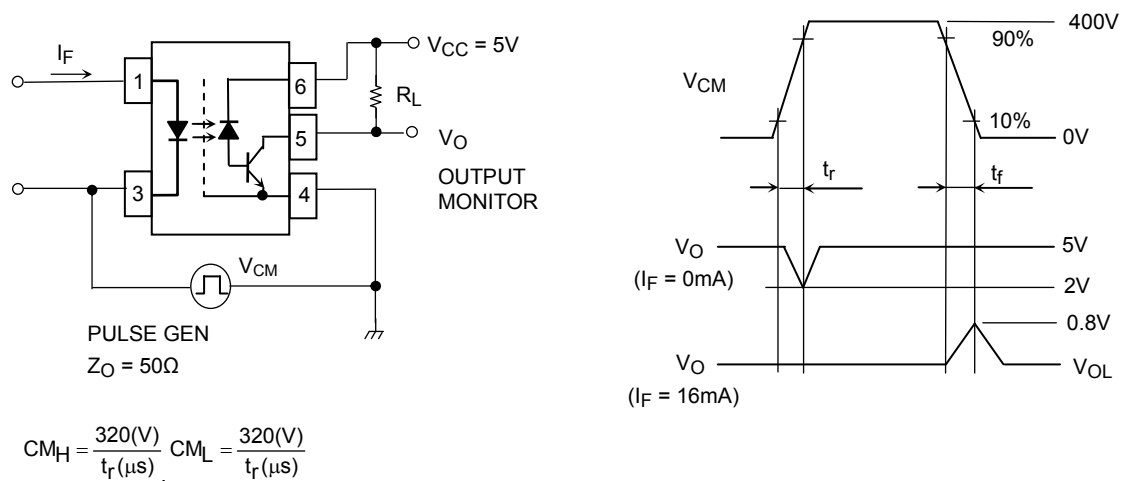
(Note 5) Device considered a two-terminal device: Pins 1 and 3 shorted together, and pins 4, 5 and 6 shorted together.

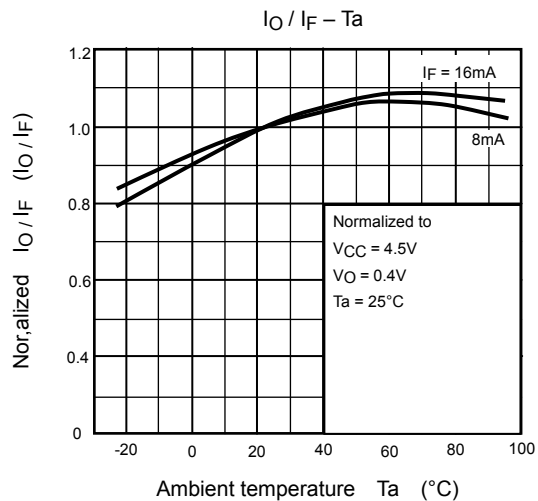
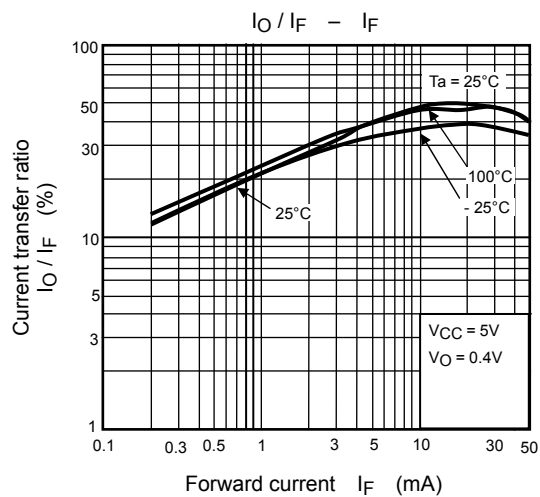
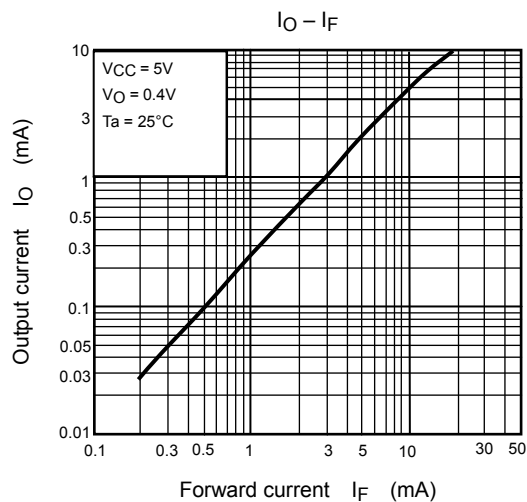
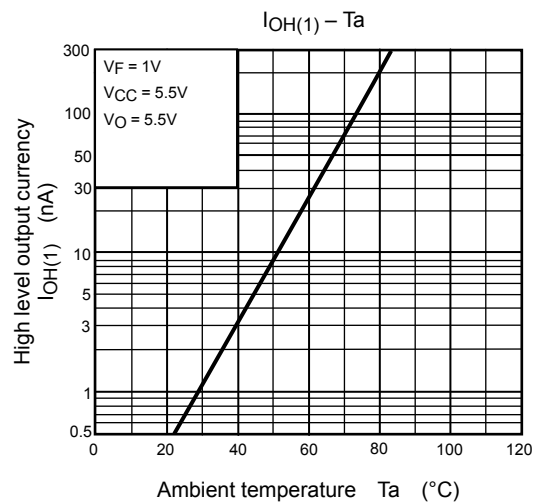
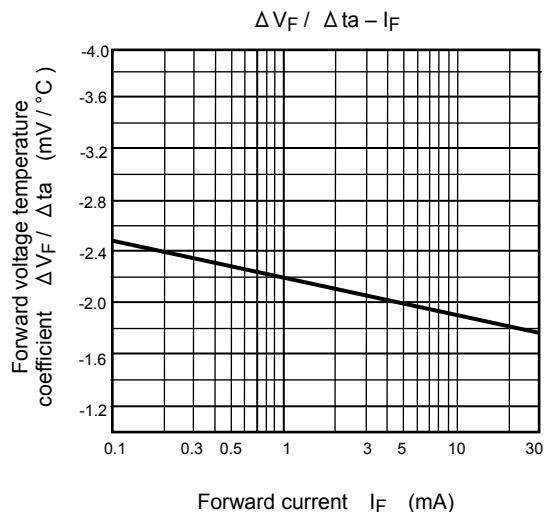
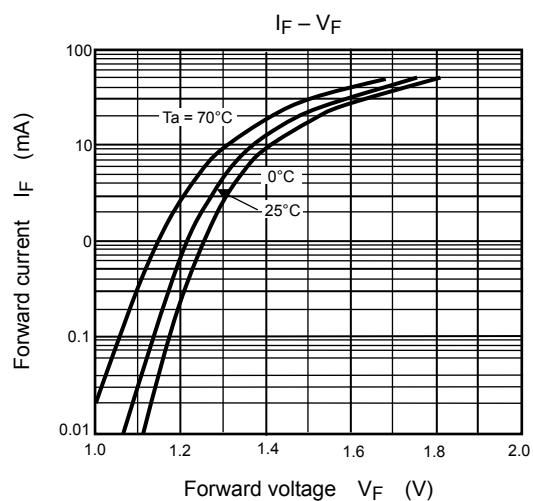
(Note 6) Maximum electrostatic discharge voltage for any pins: 100V(C=200pF, R=0)

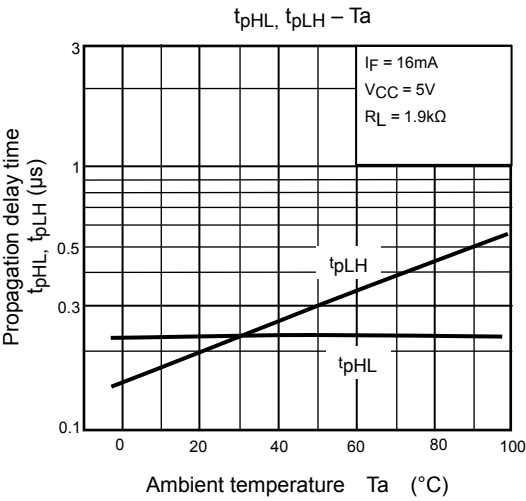
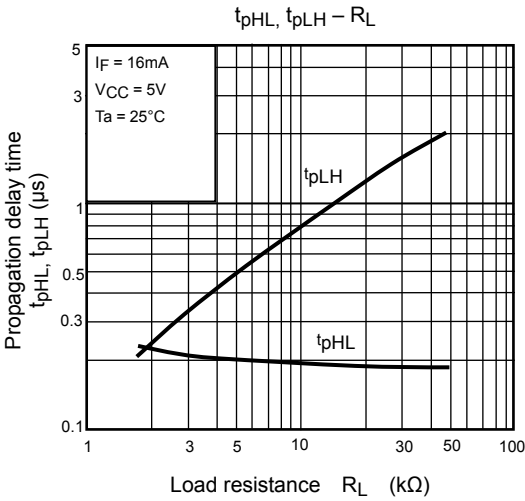
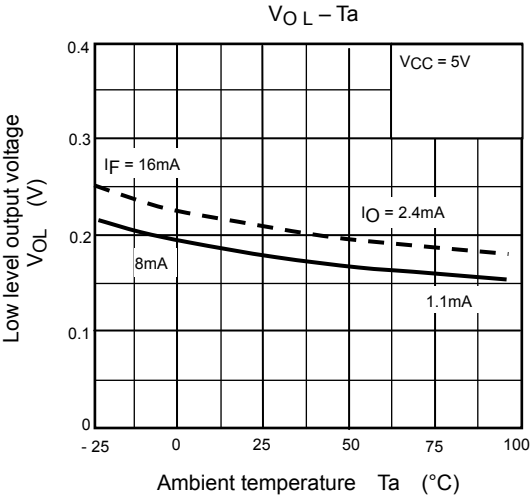
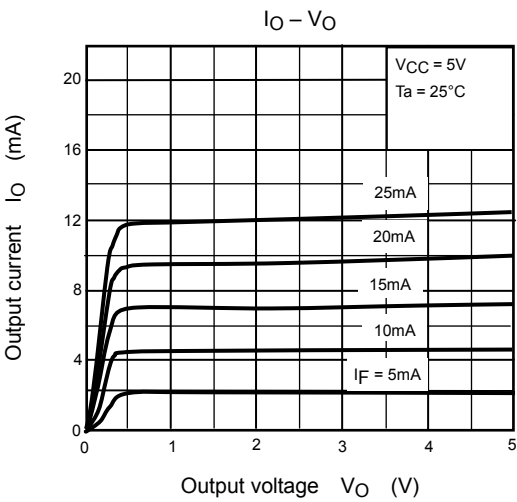
Test Circuit 1: Switching Time Test Circuit



Test Circuit =2: Common Mode Transient Immunity Test Circuit







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20070701-EN

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